

Maximize Your Semiconductor Precision and Yield with Machine Vision.

Zebra machine vision solutions, from Graftek Imaging Inc., help you improve inspection speed, accuracy, traceability and consistency across wafer, packaging, and test processes—all with powerful advanced imaging, automation, and analysis.

Smart Vision Applications in Semiconductor Manufacturing

With Zebra smart cameras, frame grabbers and Aurora software, you can achieve faster inspection, better efficiency, reduced rework and higher quality across every stage of production.



High-Speed Defect Detection

Detect surface flaws, pattern variations, and submicron defects instantly with Zebra's high-res vision sensors and frame grabbers. Identify issues early to preserve wafer yield and maintain production speed.



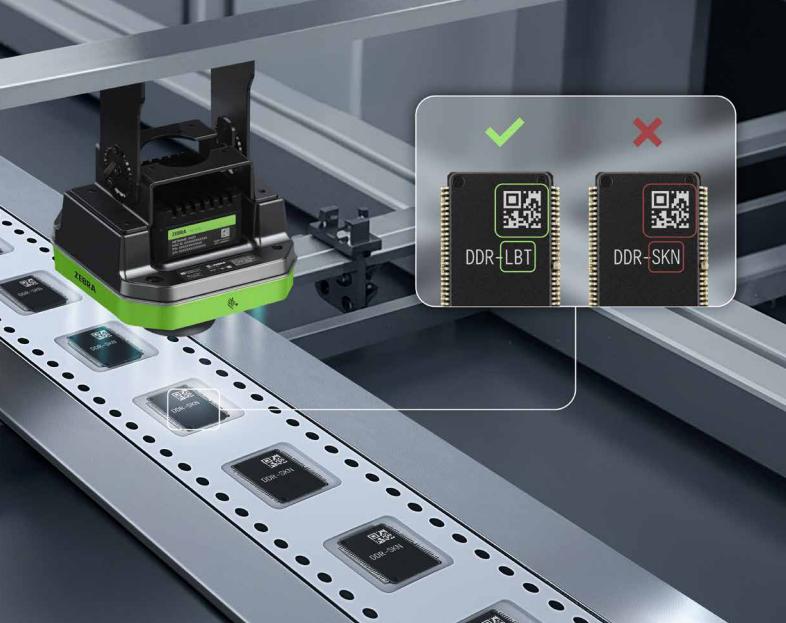
DPM and Wafer Mark Reading

Use AI-powered optical character recognition (OCR) and direct part mark (DPM) reading to identify and verify wafer IDs, marks, and codes automatically—even on reflective or low-contrast surfaces.



Packaging and Bonding Verification

Ensure accurate die bonding, alignment, and packaging integrity with flexible inspection workflows that adapt quickly to new device designs and process requirements.



Why Zebra Machine Vision?

Zebra machine vision enables true precision automation, turning data capture into actionable insight for smarter production.

With Zebra vision technology, you can modernize your inspection systems and build more reliable, data-driven processes from wafer to device.

Zebra machine vision helps you achieve better yield, traceability, and automation through advanced imaging, AI, and analytics.

Additional Key Advantages

Zebra's unified hardware and software platform offers several key advantages that help simplify integration, reduce engineering time, and ensure consistency across your inspection and automation processes.

Combined with Graftek expertise in deployment and support, you can quickly deploy and integrate this technology faster implementation, better production yield and quality, and long-term performance.

- Simplified configuration and rapid setup with Aurora software
- Seamless integration with MES and automation frameworks
- Proven accuracy in high-resolution defect detection and OCR
- Scalable systems to support future nodes and packaging types
- Reduced maintenance and total cost of ownership

Start Optimizing Your Semiconductor Production.

Connect with our machine vision experts at Graftek Imaging to learn how you can modernize your inspection systems and build more automated, reliable, data-driven production—from wafer to device.



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